

**CORNERSTONE STANDARD  
COMPONENTS LIBRARY**





# Preface

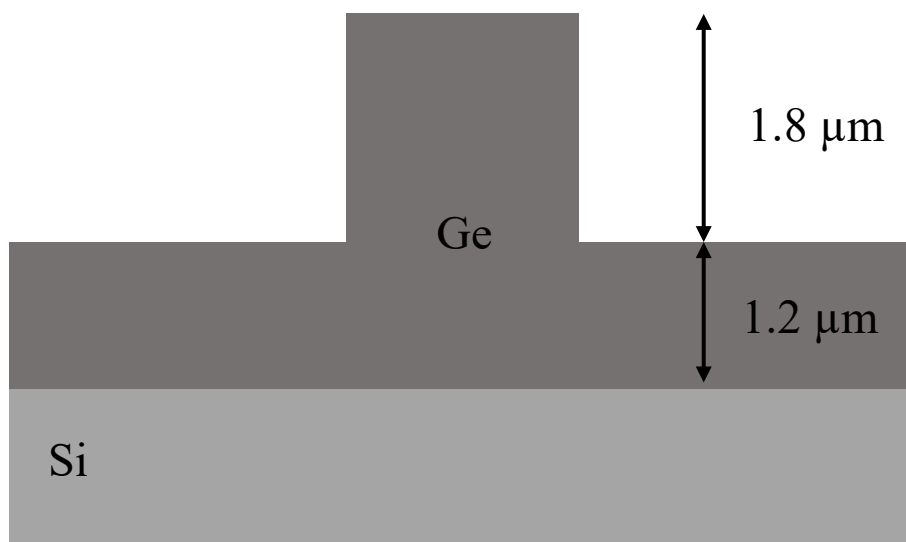
In this document, we summarized the up-to-date designs and their measurement results of our CORNERSTONE standard components on Germanium-on-Silicon (Ge-on-Si) platforms, at the same time we are optimizing the current designs, adding in new designs, and gathering more measurement results. Most of the dimensions are given in this documents, whilst a few of them are not. Thus, please use this document together with our up-to-date GDS library which can be downloaded at <https://www.cornerstone.sotonfab.co.uk/design-rules/>.



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- **Wavelength: 3800 nm**
- **Platform: Ge-on-Si**
- **RIB WAVEGUIDE**



## Ge-on-Si\_3800 nm\_TE\_Rib\_Waveguide

|                              |                                  |
|------------------------------|----------------------------------|
| <b>Platform:</b>             | Ge-on-Si                         |
| <b>Wavelength:</b>           | 3800 nm                          |
| <b>Etching depth:</b>        | 1.8 $\mu\text{m}$ (Rib design)   |
| <b>Polarization:</b>         | TE                               |
| <b>Cell name in GDS lib:</b> | Ge_on_Si_3800nm_TE_RIB_Waveguide |



## Ge-on-Si\_3800 nm\_TE\_Rib\_90\_Degree\_Bend

|                              |                                       |
|------------------------------|---------------------------------------|
| <b>Platform:</b>             | Ge-on-Si                              |
| <b>Wavelength:</b>           | 3800 nm                               |
| <b>Etching depth:</b>        | 1.8 $\mu\text{m}$ (Rib design)        |
| <b>Polarization:</b>         | TE                                    |
| <b>Cell name in GDS lib:</b> | Ge_on_Si_3800nm_TE_RIB_90_Degree_Bend |

